

<b>Notice of References Cited</b>	Application/Control No. 10/813,910		Applicant(s)/Patent Under Reexamination SCHNEIDER, RICHARD J.	
	Examiner CHRISTIAN E. RENDÓN		Art Unit 3714	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,496,032	03-1996	Okada, Kazuo	463/25
*	B	US-2003/0060280 A1	03-2003	Oles et al.	463/29
*	C	US-5,470,079	11-1995	LeStrange et al.	463/25
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	HIGH, ROBIN. Dealing With 'Outliers': How to Maintain Your Data's Integrity. Computing News (University of Oregon), Spring 2000 [online], [retrieved on 2008-1-21]. Retrieved from the Internet <URL:http://cc.uoregon.edu/cnews/spring2000/outliers.html>, pages 1-4.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.